

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Group Art Unit: To Be Assigned  
Examiner: To Be Assigned

In Re PATENT APPLICATION Of:

Applicants :	Akira TAKAHASHI	)	
Serial No. :	To Be Assigned	)	
Filed :	March 12, 2004	)	<b>INFORMATION</b>
For :	DRY ETCHING METHOD FOR SEMICONDUCTOR DEVICE	)	<b>DISCLOSURE</b>
Attorney Ref. :	OKI 414	)	<b>STATEMENT</b>

March 12, 2004

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

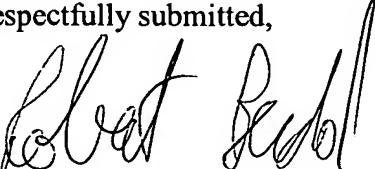
Sir:

This is an information disclosure statement submitted in compliance with the timing requirements of 37 C.F.R. §1.97(b)(1).

Attached are copies of three Japanese patent publications. Any relevance of the Japanese patent publications can be gleaned from the attached English-language Abstracts, and from page 4 of the specification of the present application, where these documents are discussed. The patent publications are listed on the attached Form PTO-1449. Also listed on the Form PTO-1449 for consideration is one U.S. patent. Any relevance of this U.S. patent is self-evident.

Since this Information Disclosure Statement is being filed with the application, no certification or fee is required, and the requirements of 37 C.F.R. §§1.97 and 1.98 are deemed to be fully met as to the listed documents. Consideration of the listed documents is respectfully requested.

Respectfully submitted,



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March 12, 2004

Date

RHB:tz

FEE ENCLOSED:\$ 4/4  
Please charge any further  
fee to our Deposit Account  
No. 18-0002

<b>FORM PTO-1449</b>  <b>INFORMATION DISCLOSURE STATEMENT</b>			Atty Docket  <b>OKI 414</b>	Application No.  <b>To Be Assigned</b>			
			Applicant  <b>Akira TAKAHASHI</b>				
			Filing Date  <b>March 12, 2004</b>	Group Unit  <b>To Be Assigned</b>			
<b>U.S. PATENT DOCUMENTS</b>							
Examiner Initial		Document Number	Date	Name	Class	Sub-Class	Filing Date
	AA	<b>6,175,136</b>	<b>01/16/01</b>	<b>Okamura</b>			
	AB						
	AC						
	AD						
	AE						
	AF						
	AC						
	AH						
	AI						
	AJ						
<b>FOREIGN PATENT DOCUMENTS</b>							
		Document Number	Date	Country	Class	Sub-Class	Trans-lation
	AK	<b>2000-164732</b>	<b>06/16/00</b>	<b>Japan</b>			<b>Abstract</b>
	AL	<b>2000-058511</b>	<b>02/25/00</b>	<b>Japan</b>			<b>Abstract</b>
	AM	<b>11-204506</b>	<b>07/30/99</b>	<b>Japan</b>			<b>Abstract</b>
	AN						
<b>OTHER (Including Author, Title, Date, Pertinent Pages, etc.)</b>							
	AO						
	AP						
	AQ						
	AR						
Examiner				Date Considered			
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.							